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|---------------------|---------------|---|---|
| Firing Tests: | E417.25(j)(1) | | |
| All-Fire Current: | E417.25(j)(2) | | |
| Ambient-temperature | E417.25(j)(5) | 1 | 3 |
| High-temperature | E417.25(j)(6) | 2 | 3 |
| Low-temperature | E417.25(j)(7) | 2 | 4 |

(1) This test must subject each electro-explosive device sample to the qualification environmental test level. For an electro-explosive device that is internal to a safe-and-arm device, the test level must be no less than the environment that the electro-explosive device experiences when installed in a safe-and-arm device subjected to the safe-and-arm device's qualification environment.

(2) For each column, the quantity of sample electro-explosive devices required at the top of the column must be from the same production lot and must undergo each test designated with an X. For a test designated with a lesser quantity, each electro-explosive device tested must be one of the original samples for that column.

(3) Five electro-explosive devices from the same lot must undergo the tests required by this column to extend the service-life of the remaining electro-explosive devices from the same lot for one year.

(4) Ten electro-explosive devices from the same lot must undergo the tests required by this column to extend the service-life of the remaining electro-explosive devices from the same lot for three years.

(5) In order to extend the service-life of an electro-explosive device, the device must undergo the tests required by the one-year column or the three-year column before the device's initial service-life or any previous service-life extension expires.